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Bib Data Sheet

CONFIRMATION NO. 8664

SERIAL NUMBER 10/810,209	FILING DATE 03/26/2004 RULE	CLASS 216	GROUP ART UNIT 1765	ATTORNEY DOCKET NO. LAM2P466
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APPLICANTS

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** CONTINUING DATA *****

none / ~~NA~~

** FOREIGN APPLICATIONS *****

none / ~~NA~~

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** 06/05/2004

Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	STATE OR	SHEETS	TOTAL	INDEPENDENT
35 USC 119 (a-d) conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after Allowance	COUNTRY	DRAWING	CLAIMS	CLAIMS
Verified and Acknowledged Examiner's Signature <u><i>Alvarez</i></u> Initials _____	CA	9	41	6

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TITLE

Method and apparatus for measurement of thin films and residues on semiconductor substrates

FILING FEE RECEIVED 1406	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
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